

Notice of References Cited	Application/Control No. 10/542,585		Applicant(s)/Patent Under Reexamination HUTTER ET AL.	
	Examiner ALINA N. BOUTAH		Art Unit 2443	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2001/0032273 A1	10-2001	Cheng, Doreen Yining	709/249
*	B	US-2001/0051930 A1	12-2001	Nakamura, Ikuo	705/56
*	C	US-2002/0004711 A1	01-2002	Sato et al.	702/188
*	D	US-6,349,352 B1	02-2002	Lea, Rodger J.	710/72
*	E	US-2002/0083143 A1	06-2002	Cheng, Doreen Yining	709/208
*	F	US-2002/0078161 A1	06-2002	Cheng, Doreen Yining	709/208
*	G	US-2003/0016682 A1	01-2003	Cho, Song-Yean	370/401
*	H	US-2003/0063608 A1	04-2003	Moonen, Jan Renier	370/390
*	I	US-2003/0110334 A1	06-2003	Lanigan et al.	710/72
*	J	US-2003/0106062 A1	06-2003	Shteyn et al.	725/78
*	K	US-2003/0110298 A1	06-2003	Lanigan, Peter J.	709/246
*	L	US-6,618,764 B1	09-2003	Shteyn, Yevgeniy Eugene	709/249
*	M	US-2005/0010689 A1	01-2005	Henry et al.	709/246

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.